



SEMI Standards PV Materials Technical Committee

Europe Chapter

Munich ICM
Tuesday, Nov 12, 2019
12:30 – 14:00 CEST

AGENDA

Co-chairs: Christian Hagendorf (FhG-CSP) and Peter Wagner (Self)

1. Welcome / Call to Order 12:30
 - 1.1. Introductions
 - 1.2. Meeting Reminders (Membership Requirement, Antitrust and Intellectual Property Reminders, Effective Meeting Guidelines)
 - 1.3. Agenda Review
2. Review and Approval of Previous Meeting Minutes (SEMI Staff) 12:35
3. Liaison Reports (SEMI Staff) 12:40
4. Staff Report (SEMI Staff) 12:00
5. Ballot Adjudication 13:00
 - 5.1. 6543 Reapproval of SEMI PV42-0314: Test Method for In-Line Measurement of Waviness of PV Silicon Wafers by a Light Sectioning Technique Using Multiple Line Segments
 - 5.2. 6544 Reapproval of SEMI PV51-0214: Test Method for In-Line Characterization of Photovoltaic Silicon Wafers by Using Photoluminescence
 - 5.3. 6545 Reapproval of SEMI PV52-0214: Test Method for In-Line Characterization of Photovoltaic Silicon Wafers Regarding Grain Size
 - 5.4. 6373 New Standard: Test Method For Accelerated Cell Level Testing For Light And Elevated Temperature Induced Degradation (LeTID) Susceptibility Of Solar Cells
6. Subcommittee & Task Force Reports 13:30
 - 6.1. PV Materials Degradation TF
 - 6.2. PV Si Materials TF
7. Old Business 13:40
8. New Business 13:45



9. Action Item Review	13:50
9.1 Open Action Items	
9.2 New Action Items	
10. Next Meeting and Adjournment	14:00

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